

Welcome to **E-XFL.COM**

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded - Microcontrollers</u>"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	25MHz
Connectivity	EBI/EMI, I ² C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	16
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	•
RAM Size	4.25K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 15x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	24-WFQFN Exposed Pad
Supplier Device Package	24-QFN (4x4)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8sb20f64g-a-qfn24r

3.2 Power

All internal circuitry draws power from the VDD supply pin. External I/O pins are powered from the VIO supply voltage (or VDD on devices without a separate VIO connection), while most of the internal circuitry is supplied by an on-chip LDO regulator. Control over the device power can be achieved by enabling/disabling individual peripherals as needed. Each analog peripheral can be disabled when not in use and placed in low power mode. Digital peripherals, such as timers and serial buses, have their clocks gated off and draw little power when they are not in use.

Table 3.1. Power Modes

Power Mode	Details	Mode Entry	Wake-Up Sources
Normal	Core and all peripherals clocked and fully operational	_	_
Idle	Core haltedAll peripherals clocked and fully operationalCode resumes execution on wake event	Set IDLE bit in PCON0	Any interrupt
Suspend	Core and digital peripherals halted Internal oscillators disabled Code resumes execution on wake event	1. Switch SYSCLK to HFOSC0 or LPOSC0 2. Set SUSPEND bit in PMU0CF	RTC0 Alarm Event RTC0 Fail Event Port Match Event Comparator 0 Rising Edge
Sleep	 Most internal power nets shut down Select circuits remain powered Pins retain state All RAM and SFRs retain state Code resumes execution on wake event 	Disable unused analog peripherals Set SLEEP bit in PMU0CF	RTC0 Alarm Event RTC0 Fail Event Port Match Event Comparator 0 Rising Edge

3.3 I/O

Digital and analog resources are externally available on the device's multi-purpose I/O pins. Port pins P0.0-P2.6 can be defined as general-purpose I/O (GPIO), assigned to one of the internal digital resources through the crossbar or dedicated channels, or assigned to an analog function. Port pin P2.7 can be used as GPIO. Additionally, the C2 Interface Data signal (C2D) is shared with P2.7.

- Up to 24 multi-functions I/O pins, supporting digital and analog functions.
- · Flexible priority crossbar decoder for digital peripheral assignment.
- · Two drive strength settings for each pin.
- · Two direct-pin interrupt sources with dedicated interrupt vectors (INT0 and INT1).
- · Up to 16 direct-pin interrupt sources with shared interrupt vector (Port Match).

3.4 Clocking

The CPU core and peripheral subsystem may be clocked by both internal and external oscillator resources. By default, the system clock comes up running from the 20 MHz low power oscillator divided by 8.

- · Provides clock to core and peripherals.
- 20 MHz low power oscillator (LPOSC0), accurate to +/- 10% over supply and temperature corners.
- 24.5 MHz internal oscillator (HFOSC0), accurate to +/- 2% over supply and temperature corners.
- External RTC 32 kHz crystal.
- External RC, C, CMOS, and high-frequency crystal clock options (EXTCLK).
- Clock divider with eight settings for flexible clock scaling: Divide the selected clock source by 1, 2, 4, 8, 16, 32, 64, or 128.

3.5 Counters/Timers and PWM

Real Time Clock (RTC0)

The RTC is an ultra low power, 36 hour 32-bit independent time-keeping Real Time Clock with alarm. The RTC has a dedicated 32 kHz oscillator. No external resistor or loading capacitors are required, and a missing clock detector features alerts the system if the external crystal fails. The on-chip loading capacitors are programmable to 16 discrete levels allowing compatibility with a wide range of crystals.

The RTC module includes the following features:

- Up to 36 hours (32-bit) of independent time keeping.
- Support for external 32 kHz crystal or internal self-oscillate mode.
- Internal crystal loading capacitors with 16 levels.
- Operation in the lowest power mode and across the full supported voltage range.
- Alarm and oscillator failure events to wake from the lowest power mode or reset the device.

Programmable Counter Array (PCA0)

The programmable counter array (PCA) provides multiple channels of enhanced timer and PWM functionality while requiring less CPU intervention than standard counter/timers. The PCA consists of a dedicated 16-bit counter/timer and one 16-bit capture/compare module for each channel. The counter/timer is driven by a programmable timebase that has flexible external and internal clocking options. Each capture/compare module may be configured to operate independently in one of five modes: Edge-Triggered Capture, Software Timer, High-Speed Output, Frequency Output, or Pulse-Width Modulated (PWM) Output. Each capture/compare module has its own associated I/O line (CEXn) which is routed through the crossbar to port I/O when enabled.

- · 16-bit time base.
- Programmable clock divisor and clock source selection.
- · Up to six independently-configurable channels
- 8, 9, 10, 11 and 16-bit PWM modes (edge-aligned operation).
- · Frequency output mode.
- · Capture on rising, falling or any edge.
- · Compare function for arbitrary waveform generation.
- Software timer (internal compare) mode.
- · Integrated watchdog timer.

Timers (Timer 0, Timer 1, Timer 2, and Timer 3)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:

- · Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- · Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- · 8-bit auto-reload counter/timer mode
- · 13-bit counter/timer mode
- 16-bit counter/timer mode
- · Dual 8-bit counter/timer mode (Timer 0)

Timer 2 and Timer 3 are 16-bit timers including the following features:

- Clock sources include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8.
- 16-bit auto-reload timer mode
- · Dual 8-bit auto-reload timer mode
- Comparator 0 or RTC0 capture (Timer 2)
- · Comparator 1 or EXTCLK/8 capture (Timer 3)

External Memory Interface (EMIF0)

The External Memory Interface (EMIF) enables access of off-chip memories and memory-mapped devices connected to the GPIO ports. The external memory space may be accessed using the external move instruction (MOVX) with the target address specified in either 8-bit or 16-bit formats.

- · Supports multiplexed memory access.
- · Four external memory modes:
 - · Internal only.
 - · Split mode without bank select.
 - · Split mode with bank select.
 - External only
- · Configurable ALE (address latch enable) timing.
- · Configurable address setup and hold times.
- · Configurable write and read pulse widths.

16/32-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit or 32-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module includes the following features:

- Support for CCITT-16 polynomial (0x1021).
- Support for CRC-32 polynomial (0x04C11DB7).
- · Byte-level bit reversal.
- · Automatic CRC of flash contents on one or more 1024-byte blocks.
- Initial seed selection of 0x0000/0x00000000 or 0xFFFF/0xFFFFFFF.

3.7 Analog

Programmable Current Reference (IREF0)

The programmable current reference (IREF0) module enables current source or sink with two output current settings: Low Power Mode and High Current Mode. The maximum current output in Low Power Mode is 63 μ A (1 μ A steps) and the maximum current output in High Current Mode is 504 μ A (8 μ A steps).

The IREF module includes the following features:

- · Capable of sourcing or sinking current in programmable steps.
- Two operational modes: Low Power Mode and High Current Mode.

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 4.1 Recommended Operating Conditions on page 11, unless stated otherwise.

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Operating Supply Voltage on VDD	V_{DD}		1.8	2.4	3.6	V
Minimum RAM Data Retention	V _{RAM}	Not in Sleep Mode	_	1.4	_	V
Voltage on VDD ¹		Sleep Mode	_	0.3	0.5	V
System Clock Frequency	f _{SYSCLK}		0	_	25	MHz
Operating Ambient Temperature	T _A		-4 0	_	85	°C

Note:

1. All voltages with respect to GND.

Table 4.2. Power Consumption

Parameter	Symbol	Conditions	Min	Тур	Max	Units
Digital Supply Current						
Normal Mode supply current - Full speed with code executing from	I _{DD}	V _{DD} = 1.8–3.6 V, f _{SYSCLK} = 24.5 MHz	_	4.1	5.0	mA
flash ^{3, 4, 5}		V _{DD} = 1.8–3.6 V, f _{SYSCLK} = 20 MHz	_	3.5	_	mA
		V _{DD} = 1.8–3.6 V, f _{SYSCLK} = 32.768 kHz	_	90	_	μA
Normal Mode supply current frequency sensitivity ^{1, 3, 5}	I _{DDFREQ}	V _{DD} = 1.8–3.6 V, T = 25 °C, f _{SYSCLK} < 14 MHz	_	226	_	μΑ/MHz
		V _{DD} = 1.8–3.6 V, T = 25 °C, f _{SYSCLK} > 14 MHz	_	120		μA/MHz
Idle Mode supply current - Core halted with peripherals running ⁴ , ⁶	I _{DD}	V _{DD} = 1.8–3.6 V, f _{SYSCLK} = 24.5 MHz	_	2.5	3.0	mA
		V _{DD} = 1.8–3.6 V, f _{SYSCLK} = 20 MHz	_	1.8		mA
		V _{DD} = 1.8–3.6 V, f _{SYSCLK} = 32.768 kHz	_	84		μA
Idle Mode Supply Current Frequency Sensitivity ^{1,6}	I _{DDFREQ}	V _{DD} = 1.8–3.6 V, T = 25 °C	_	95		μA/MHz
Suspend Mode Supply Current	I _{DD}	V _{DD} = 1.8–3.6 V	_	77	_	μA
Sleep Mode Supply Current with	I _{DD}	1.8 V, T = 25 °C	_	0.60	_	μA
RTC running from 32.768 kHz crystal		3.6 V, T = 25 °C	_	0.85	_	μA
		1.8 V, T = 85 °C	_	1.30	_	μA
		3.6 V, T = 85 °C	_	1.90	_	μA

Parameter	Symbol	Conditions	Min	Тур	Max	Units
Sleep Mode Supply Current (RTC	I _{DD}	1.8 V, T = 25 °C	_	0.05	_	μA
off)		3.6 V, T = 25 °C	_	0.12	_	μA
		1.8 V, T = 85 °C	_	0.75	_	μA
		3.6 V, T = 85 °C	_	1.20	_	μA
V _{DD} Monitor Supply Current	I _{VMON}		_	7	_	μA
Oscillator Supply Current	I _{HFOSC0}	25 °C	_	300	_	μA
ADC0 Always-on Power Supply	I _{ADC}	300 ksps	_	800	_	μA
Current ⁷		V _{DD} = 3.0 V				
		Tracking	_	680	_	μA
		V _{DD} = 3.0 V				
Comparator 0 (CMP0) Supply Cur-	I _{CMP}	CPMD = 11	_	0.4	_	μA
rent		CPMD = 10	_	2.6	_	μA
		CPMD = 01	_	8.8	_	μA
		CPMD = 00	_	23	_	μA
Internal Fast-settling 1.65V ADC0 Reference, Always-on ⁸	I _{VREFFS}		_	200	_	μA
On-chip Precision Reference	I _{VREFP}		_	15	_	μA
Temp sensor Supply Current	I _{TSENSE}		_	35	_	μA
Programmable Current Reference (IREF0) Supply Current ⁹	I _{IREF}	Current Source, Either Power Mode, Any Output Code	_	10	_	μA
		Low Power Mode, Current Sink	_	1	_	μA
		IREF0DAT = 000001				
		Low Power Mode, Current Sink	_	11	_	μA
		IREF0DAT = 111111				
		High Current Mode, Current Sink	_	12	_	μA
		IREF0DAT = 000001				
		High Current Mode, Current Sink	_	81	_	μA
		IREF0DAT = 111111				

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Temperature Coefficient	TC _{REFFS}		_	50	_	ppm/°C
Turn-on Time	t _{VREFFS}		_	_	1.5	μs
Power Supply Rejection	PSRR _{REF} FS		_	400	_	ppm/V
On-chip Precision Reference						
Output Voltage	V _{REFP}		1.645	1.68	1.715	V
Turn-on Time, settling to 0.5 LSB	t _{VREFP}	4.7 μF tantalum + 0.1 μF ceramic bypass on VREF pin	_	15	_	ms
		0.1 μF ceramic bypass on VREF pin	_	300	_	μs
		No bypass on VREF pin	_	25	_	μs
Load Regulation	LR _{VREFP}	Load = 0 to 200 µA to GND	_	400	_	μV / μΑ
Short-circuit current	ISC _{VREFP}		_	3.5	_	mA
Power Supply Rejection	PSRR _{VRE} FP		_	140	_	ppm/V
External Reference						
Input Voltage	V _{EXTREF}		1	_	V _{DD}	V
Input Current	I _{EXTREF}	Sample Rate = 300 ksps; VREF = 3.0 V	_	5.25	_	μА

Table 4.11. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Offset	V _{OFF}	T _A = 0 °C	_	940	_	mV
Offset Error ¹	E _{OFF}	T _A = 0 °C	_	18	_	mV
Slope	М		_	3.40	_	mV/°C
Slope Error ¹	E _M		_	40	_	μV/°C
Linearity			_	±1	_	°C
Turn-on Time	t _{PWR}		_	1.8	_	μs
Note:	1		-1	1	1	1

Table 4.12. Comparators

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t _{RESP0}	+100 mV Differential	_	130	_	ns
		-100 mV Differential	_	200	_	ns
Response Time, CPMD = 11 (Low-	t _{RESP3}	+100 mV Differential	_	1.75	_	μs
est Power)		-100 mV Differential	_	6.2	_	μs

1. Represents one standard deviation from the mean.

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Input Offset Tempco	TC _{OFF}		_	3.5	_	μV/°C

Table 4.13. Programmable Current Reference (IREF0)

Parameter	Symbol	Conditions	Min	Тур	Max	Units
Static Performance	'					
Resolution	N _{bits}			6		bits
Output Compliance Range	V _{IOUT}	Low Power Mode, Source	0	_	V _{DD} – 0.4	V
		High Current Mode, Source	0	_	V _{DD} – 0.8	V
		Low Power Mode, Sink	0.3	_	V _{DD}	V
		High Current Mode, Sink	0.8	_	V _{DD}	V
Integral Nonlinearity	INL		_	<±0.2	±1.0	LSB
Differential Nonlinearity	DNL		_	<±0.2	±1.0	LSB
Offset Error	E _{OFF}		_	<±0.1	±0.5	LSB
Full Scale Error	E _{FS}	Low Power Mode, Source	_	_	±5	%
		High Current Mode, Source	_	_	±6	%
		Low Power Mode, Sink	_	_	±8	%
		High Current Mode, Sink	_	_	±8	%
Absolute Current Error	E _{ABS}	Low Power Mode Sourcing 20 μA	_	<±1	±3	%
Dynamic Performance	1	<u>'</u>	1	1	1	
Output Settling Time to 1/2 LSB	t _{SETTLE}		_	300	_	ns
Startup Time	t _{PWR}		_	1	_	μs
Note:			1	1		

Table 4.14. Port I/O

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Output High Voltage (High Drive)	V _{OH}	I _{OH} = -3 mA	V _{DD} – 0.7	_	_	V
Output Low Voltage (High Drive)	V _{OL}	I _{OL} = 8.5 mA	_	_	0.6	V
Output High Voltage (Low Drive)	V _{OH}	I _{OH} = -1 mA	V _{DD} – 0.7	_	_	V
Output Low Voltage (Low Drive)	V _{OL}	I _{OL} = 1.4 mA	_	_	0.6	V
Input High Voltage	V _{IH}	V _{DD} = 2.0 to 3.6 V	V _{DD} – 0.6	_	_	V
		V _{DD} = 1.8 to 2.0 V	0.7 x V _{DD}	_	_	V
Input Low Voltage	V _{IL}	V _{DD} = 2.0 to 3.6 V	_	_	0.6	V
		V _{DD} = 1.8 to 2.0 V	_	_	0.3 x V _{DD}	V

^{1.} The PCA block may be used to improve IREF0 resolution by PWMing the two LSBs.

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Weak Pull-Up Current	I _{PU}	V _{DD} = 1.8 V	_	-4	_	μA
		V _{IN} = 0 V				
		V _{DD} = 3.6 V	-35	-20	_	μΑ
		V _{IN} = 0 V				
Input Leakage	I _{LK}	Weak pullup disabled or pin in analog mode	-1	_	1	μА

4.2 Thermal Conditions

Table 4.15. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Thermal Resistance ¹	θ_{JA}	QFN-24 Packages	_	35	_	°C/W
		QFN-32 Packages	_	28	_	°C/W
		QFP-32 Packages	_	80	_	°C/W

Note:

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.16 Absolute Maximum Ratings on page 19 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.16. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T _{BIAS}		-55	125	°C
Storage Temperature	T _{STG}		-65	150	°C
Voltage on V _{DD}	V _{DD}		GND-0.3	4.0	V
Voltage on I/O pins or RSTb	V _{IN}	V _{DD} > 2.2 V	GND-0.3	5.8	V
		V _{DD} <= 2.2 V	GND-0.3	V _{DD} + 3.6	V
Total Current Sunk into Supply Pin	I _{VDD}		_	400	mA
Total Current Sourced out of Ground Pin	I _{GND}		400	_	mA
Current Sourced or Sunk by Any I/O Pin or RSTb	I _{IO}		-100	100	mA
Maximum Total Current through all Port Pins	I _{IOTOT}		_	200	mA
Operating Junction Temperature	TJ		-40	105	°C
Exposure to maximum rating conditions	s for extended	d periods may affect device reliability.	1		

^{1.} Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

5. Typical Connection Diagrams

5.1 Power

Figure 5.1 Power Connection Diagram on page 22 shows a typical connection diagram for the power pins of the EFM8SB2 devices.

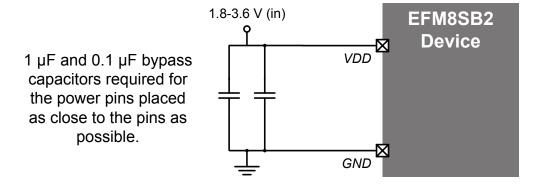


Figure 5.1. Power Connection Diagram

5.2 Other Connections

Other components or connections may be required to meet the system-level requirements. Application Note AN203: "8-bit MCU Printed Circuit Board Design Notes" contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website (www.silabs.com/8bit-appnotes).

6. Pin Definitions

6.1 EFM8SB2x-QFN32 Pin Definitions

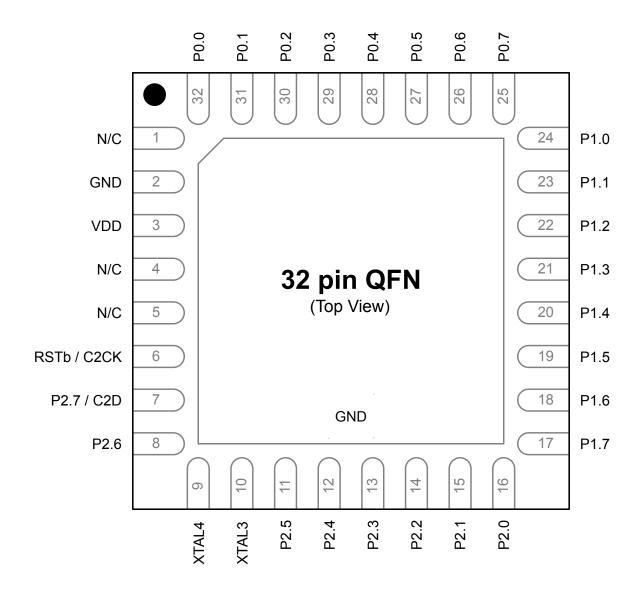


Figure 6.1. EFM8SB2x-QFN32 Pinout

Table 6.1. Pin Definitions for EFM8SB2x-QFN32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	GND	Ground			
3	VDD	Supply Power Input			
4	N/C	No Connection			

Pin	Pin Name	Description	Crossbar Capability	Additional Digital	Analog Functions
Number				Functions	
19	P1.5	Multifunction I/O	Yes	P1MAT.5	ADC0.13
				EMIF_AD5	CMP0N.6
					CMP1N.6
20	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12
				EMIF_AD4	CMP0P.6
					CMP1P.6
21	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11
				SPI1_NSS	CMP0N.5
				EMIF_AD3	CMP1N.5
22	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10
				SPI1_MOSI	CMP0P.5
				EMIF_AD2	CMP1P.5
23	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9
				SPI1_MISO	CMP0N.4
				EMIF_AD1	CMP1N.4
24	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8
				SPI1_SCK	CMP0P.4
				EMIF_AD0	CMP1P.4
25	P0.7	Multifunction I/O	Yes	P0MAT.7	ADC0.7
				INT0.7	IREF0
				INT1.7	CMP0N.3
					CMP1N.3
26	P0.6	Multifunction I/O	Yes	P0MAT.6	ADC0.6
				CNVSTR	CMP0P.3
				INT0.6	CMP1P.3
				INT1.6	
27	P0.5	Multifunction I/O	Yes	P0MAT.5	ADC0.5
				INT0.5	CMP0N.2
				INT1.5	CMP1N.2
28	P0.4	Multifunction I/O	Yes	P0MAT.4	ADC0.4
				INT0.4	CMP0P.2
				INT1.4	CMP1P.2
29	P0.3	Multifunction I/O	Yes	P0MAT.3	ADC0.3
				EXTCLK	XTAL2
				INT0.3	CMP0N.1
				INT1.3	CMP1N.1

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
19	P0.5	Multifunction I/O	Yes	P0MAT.5	ADC0.5
				INT0.5	CMP0N.2
				INT1.5	CMP1N.2
20	P0.4	Multifunction I/O	Yes	P0MAT.4	ADC0.4
				INT0.4	CMP0P.2
				INT1.4	CMP1P.2
21	P0.3	Multifunction I/O	Yes	P0MAT.3	ADC0.3
				EXTCLK	XTAL2
				INT0.3	CMP0N.1
				INT1.3	CMP1N.1
22	P0.2	Multifunction I/O	Yes	P0MAT.2	ADC0.2
				INT0.2	CMP0P.1
				INT1.2	CMP1P.1
					XTAL1
23	P0.1	Multifunction I/O	Yes	P0MAT.1	ADC0.1
				INT0.1	AGND
				INT1.1	CMP0N.0
					CMP1N.0
24	P0.0	Multifunction I/O	Yes	P0MAT.0	ADC0.0
				INT0.0	CMP0P.0
				INT1.0	CMP1P.0
					VREF
Center	GND	Ground			

Dimension	Min	Тур	Max
bbb	_	_	0.10
ddd	_	_	0.05
eee	_	_	0.08

Note:

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
- 3. This drawing conforms to JEDEC Solid State Outline MO-220, variation VHHD except for custom features D2, E2, and L which are toleranced per supplier designation.
- 4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

7.2 QFN32 PCB Land Pattern

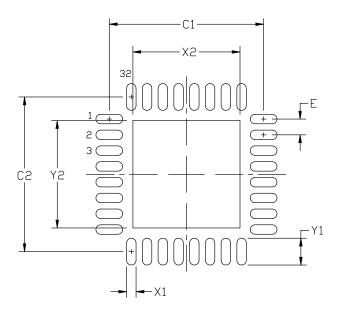


Figure 7.2. QFN32 PCB Land Pattern Drawing

Table 7.2. QFN32 PCB Land Pattern Dimensions

Dimension	Min	Max							
C1	4.80	4.90							
C2	4.80	4.90							
E	0.50 BSC								
X1	0.20	0.30							
X2	3.20	3.40							
Y1	0.75	0.85							
Y2	3.20	3.40							

Note:

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. This Land Pattern Design is based on the IPC-7351 guidelines.
- 3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be $60 \mu m$ minimum, all the way around the pad.
- 4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 5. The stencil thickness should be 0.125 mm (5 mils).
- 6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
- 7. A 3 x 3 array of 1.0 mm x 1.0 mm openings on a 1.2 mm pitch should be used for the center pad.
- 8. A No-Clean, Type-3 solder paste is recommended.
- 9. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

7.3 QFN32 Package Marking



Figure 7.3. QFN32 Package Marking

The package marking consists of:

- PPPPPPP The part number designation.
- TTTTTT A trace or manufacturing code.
- YY The last 2 digits of the assembly year.
- WW The 2-digit workweek when the device was assembled.
- # The device revision (A, B, etc.).

Dimension Min Max

Note:

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. This Land Pattern Design is based on the IPC-7351 guidelines.
- 3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μ m minimum, all the way around the pad.
- 4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 5. The stencil thickness should be 0.125 mm (5 mils).
- 6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
- 7. A 2 x 2 array of 1.10 mm x 1.10 mm openings on 1.30 mm pitch should be used for the center ground pad.
- 8. A No-Clean, Type-3 solder paste is recommended.
- 9. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

8.3 QFN24 Package Marking

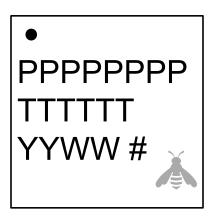


Figure 8.3. QFN24 Package Marking

The package marking consists of:

- PPPPPPP The part number designation.
- TTTTTT A trace or manufacturing code.
- · YY The last 2 digits of the assembly year.
- WW The 2-digit workweek when the device was assembled.
- # The device revision (A, B, etc.).

9. QFP32 Package Specifications

9.1 QFP32 Package Dimensions

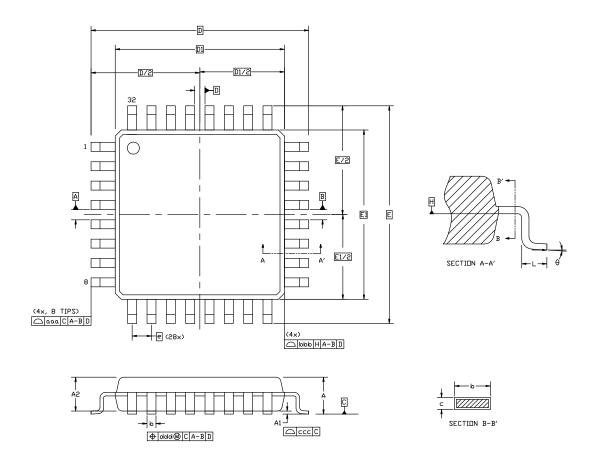


Figure 9.1. QFP32 Package Drawing

Table 9.1. QFP32 Package Dimensions

Dimension	Min	Тур	Max							
А	_	_	1.60							
A1	0.05	_	0.15							
A2	1.35	1.40	1.45							
b	0.30	0.37	0.45							
D	9.00 BSC									
D1		7.00 BSC								
е		0.80 BSC								
Е		9.00 BSC								
E1		7.00 BSC								
L	0.45	0.60	0.75							
aaa	0.20									

Dimension	Min	Тур	Max							
bbb		0.20								
ccc		0.10								
ddd		0.20								
theta	0°	3.5°	7°							

Note:

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
- 3. This drawing conforms to JEDEC outline MS-026, variation BBA.
- 4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

9.3 QFP32 Package Marking

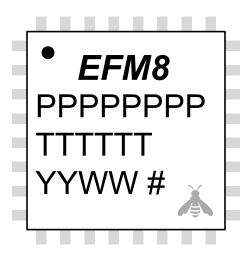


Figure 9.3. QFP32 Package Marking

The package marking consists of:

- PPPPPPP The part number designation.
- TTTTTT A trace or manufacturing code.
- YY The last 2 digits of the assembly year.
- WW The 2-digit workweek when the device was assembled.
- # The device revision (A, B, etc.).

9.2 QFP32 PCB Land Pattern .													.44
9.3 QFP32 Package Marking .					•	•							.45
Γable of Contents													46